

# **Notice of References Cited**

Application/Control No.

09/751,468

Applicant(s)/Patent Under  
Reexamination  
STEFANIK, JOHN R.

Examiner

Daniel Previl

Art Unit

2632

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## **U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
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